



#8/5
G88
8/13/02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Shing Lee, Haiming Wang, Adam E. Norton, Mehrdad Nikoonahad

Assignee: KLA-Tencor Corporation

Title: SYSTEM FOR MEASURING POLARIMETRIC SPECTRUM AND OTHER PROPERTIES OF A SAMPLE

Serial No.: 09/778,245 Filing Date: February 6, 2001

Examiner: Hoa Q. Pham Group Art Unit: 2877

Docket No.: M-10685-1C US

San Francisco, California
July 29, 2002

BOX Fee Amendment
COMMISSIONER FOR PATENTS
Washington, DC 20231

AMENDMENT

Dear Sir:

This responds to the Office Action mailed on January 28, 2002, setting a period for response expiring on April 28, 2002. Attached is a request for extension of time to extend the response period to July 29, 2002, July 28, 2002 being a Sunday.

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TECHNOLOGY CENTER 2800

08/13/2002 ATTORNEY 00000002 192386 09778245
01 FC:102 251.00 CH

Please amend the above-referenced application as follows:

IN THE CLAIMS:

Please cancel claims 1-88 and add new claims 89-337 as follows:

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01 FC:103 2891.00 CH
02 FC:102 750.00 CH

89. A method for measuring optically detectable properties of a sample, comprising:

focusing a polarized sample beam of broadband radiation onto the sample, said beam

having a multitude of polarization states;

collecting radiation modified by the sample by means of an objective; and

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